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Terms	Documents
L20 and (select$4 same portion$3)	0

1114
8.13.4

Database: US Pre-Grant Publication Full-Text Database; US Patents Full-Text Database; US OCR Full-Text Database; EPO Abstracts Database; JPO Abstracts Database; Derwent World Patents Index; IBM Technical Disclosure Bulletins

Search: L22

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Search History

DATE: Friday, August 13, 2004 Printable Copy Create Case

Set Name side by side	Query	Hit Count	Set Name result set
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L22	L20 and (select$4 same portion$3)	0	L22
L21	L20 and (select$3 same portion$)	0	L21
L20	L19 and (creat$3 or recreat$3 or construct$3 or reconstruct$3)	2	L20
L19	L18 not L14	2	L19
L18	L17 not L13	2	L18
L17	L16 and (partition$3 near table$1)	3	L17
L16	L15 and (L2 or L3)	48	L16
L15	707/$.ccls.	21907	L15
L14	L11 and (partition$3 near table$1)	1	L14
L13	L11 and (partition$3 same table$1)	3	L13
L12	L11 and partition$3	7	L12
L11	(L2 or L3) and (data near dictionary)	12	L11
DB=USPT; PLUR=YES; OP=OR			

L10	6163776.pn.	1	L10
L9	6591272.pn.	1	L9
DB=PGPB; PLUR=YES; OP=OR			
L8	20020143727.pn.	1	L8
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L7	L6 not L5	3	L7
L6	(L2 or L3) and (DDL or (data near description near language))	5	L6
L5	(L2 or L3) and ((DDL or (data near description near language)) same command$1)	2	L5
L4	L3 not L2	0	L4
L3	"dump file"	376	L3
L2	dump$ near file	530	L2
L1	(DDL or (data near description near language)) same command$1 same (dump$ near file)	1	L1

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Search Results -

Terms	Documents
L11 and (partition$3 near table$1)	1

1-14
8.13.4

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US Patents Full-Text Database
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L13	L11 and (partition$3 same table$1)	3	L13
L12	L11 and partition$3	7	L12
L11	(L2 or L3) and (data near dictionary)	12	L11
DB=USPT; PLUR=YES; OP=OR			
L10	6163776.pn.	1	L10
L9	6591272.pn.	1	L9
DB=PGPB; PLUR=YES; OP=OR			
L8	20020143727.pn.	1	L8
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L7	L6 not L5	3	L7
L6	(L2 or L3) and (DDL or (data near description near language))	5	L6
	(L2 or L3) and ((DDL or (data near description near language)) same		

L5	command$1)	2	L5
L4	L3 not L2	0	L4
L3	"dump file"	376	L3
L2	dump$ near file	530	L2
L1	(DDL or (data near description near language)) same command$1 same (dump$ near file)	1	L1

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Search Results - Record(s) 1 through 1 of 1 returned.

☐ 1. Document ID: US 6240428 B1

Using default format because multiple data bases are involved.

L14: Entry 1 of 1 File: USPT May 29, 2001

US-PAT-NO: 6240428
DOCUMENT-IDENTIFIER: US 6240428 B1

TITLE: Import/export and repartitioning of partitioned objects

DATE-ISSUED: May 29, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Yeung; Sofia	Union City	CA		
Chang; Chung	San Jose	CA		

US-CL-CURRENT: 707/206

Full | Title | Citation | Front | Review | Classification | Date | Reference | Claims | KWIC | Draw. D

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Terms	Documents
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